# SN54LS266, SN74LS266 QUADRUPLE 2-INPUT EXCLUSIVE-NOR GATES WITH OPEN-COLLECTORS OUTPUTS DECEMBER 1972 - REVISED MARCH 1988

**SDLS151** 

- · Can Be Used as a 4-Bit Digital Comparator
- Input Clamping Diodes Simplify System Design
- Fully Compatible with Most TTL Circuits

FUNCTION TABLE



н = high level, L = low level

## description

The 'LS266 is comprised of four independent 2-input exclusive-NOR gates with open-collector outputs. The open-collector outputs permit tying outputs together for multiple-bit comparisons.

#### logic symbol (each gate)



logic symbol<sup>†</sup>



positive logic:  $Y = \overline{A \oplus B} = AB + \overline{AB}$ 

<sup>†</sup>This symbol is in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12.

Pin numbers shown are for D, J, N, and W packages.

SN74LS266	J OR W PACKAGE D OR N PACKAGE VIEW)
1A []	14 VCC
1B []	13 4B
1Y []	12 4A
2Y [] 4	11 4Y
2A [] 5	10 3Y
2B [] 6	9 3B
GND [] 7	8 3A

SN54LS266 ... FK PACKAGE (TOP VIEW)



NC - No internal connection

#### schematic of inputs and outputs



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# SN54LS266, SN74LS266 **QUADRUPLE 2-INPUT EXCLUSIVE-NOR GATES** WITH OPEN-COLLECTOR OUTPUTS

# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)												
Operating free-air temperature range:	SN54LS266										-55°C to 12	25°C
	SN74LS266						•				. 0°C to 7	70°C
Storage temperature range								,			-65°C to 15	50°C

NOTE 1: Voltage values are with respect to network ground terminal.

## recommended operating conditions

	SI	N54LS2	66	s			
	MIN	NOM	MAX	MIN	NOM	MAX	
Supply voltage, V <sub>CC</sub>	4.5	5	5.5	4.75	5	5.25	V
High-level output voltage, VOH			5.5			5.5	V
Low-level output current, IOL			4			8	mΑ
Operating free-air temperature, TA	-55		125	0		70	С

## electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

		7507.004	S	N54LS2	66	S				
	PARAMETER	TEST COM	MIN	түр‡	MAX	MIN	ТҮР	MAX		
√ін	High-level input voltage			2			2			V
VIL	Low-level input voltage					0.7			0.8	V
VIK	Input clamp voltage	V <sub>CC</sub> = MIN,	l <sub>1</sub> = -18 mA			-1.5			-1.5	V
юн	High-level output current	V <sub>CC</sub> = MIN, V <sub>IL</sub> = V <sub>IL</sub> max,	V <sub>IH</sub> = 2 V, V <sub>OH</sub> = 5.5 V			100			109	μА
	.ow-level output voltage	$V_{CC} = MIN,$ $V_{1H} = 2 V,$	I <sub>OL</sub> = 4 mA		0.25	0.4		0.25	0.4	v
VOL	EOM-level on this course	ViL ≄ ViL max	IOL = 8 mA					0.35	0.5	
4	Input current at maximum input voltage	VCC = MAX.	VI = 7 V			0.2			0.2	mΑ
ЧΗ	High-level input current	V <sub>CC</sub> - MAX,	VI - 2.7 V			40			40	μA
կլ	Low-level input current	V <sub>CC</sub> - MAX,	V <sub>I</sub> = 0.4 V			-0.8	1		-0,8	mΑ
1cc	Supply current	V <sub>CC</sub> = MAX,	See Note 2	-	8	13	<u> </u>	8	13	mA

<sup>1</sup>For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type. <sup>†</sup>All typical values are at  $V_{CC} = 5 V$ ,  $T_{A} = 25 C$ , NOTE 2: ICC is measured with one input of each gate at 4.5 V, the other inputs grounded, and the outputs open.

# switching characteristics, VCC = 5 V, TA = 25°C

PARAMETER <sup>§</sup>	FROM (INPUT)	TEST CO	NDITIONS		МАХ	UNIT
<sup>t</sup> PLH	A or B	Other input low	Ci_ = 15 pF,	18	30	пŝ
tрнц	700		R <sub>L</sub> = 2 kΩ,	18	30	
tpLH	A or B	Other input high	See Note 3	18	30	ns
трнг				18	30	]

 ${}^{\$}$ tpLH = propagation delay time, low-to-high-level output

tpHL = propagation delay time, high-to-low-level output

NOTE 3: Load circuits and voltage waveforms are shown in Section 1



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